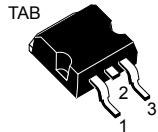
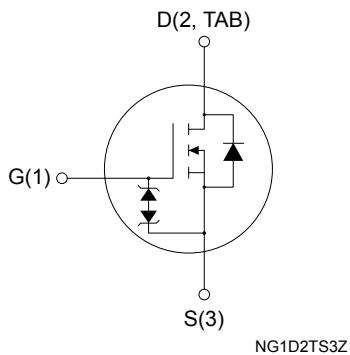


## Automotive-grade N-channel 400 V, 0.050 Ω typ., 41 A, MDmesh™ DM6 Power MOSFET in a D<sup>2</sup>PAK package

### Features

D<sup>2</sup>PAK

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STB41N40DM6AG	400 V	0.065 Ω	41 A



- AEC-Q101 qualified
- Fast-recovery body diode
- Lower R<sub>DS(on)</sub> per area vs previous generation
- Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### Applications

- Switching applications

### Description

This high-voltage N-channel Power MOSFET is part of the MDmesh™ DM6 fast-recovery diode series. Compared with the previous MDmesh fast generation, DM6 combines very low recovery charge ( $Q_{rr}$ ), recovery time ( $t_{rr}$ ) and excellent improvement in  $R_{DS(on)}$  per area with one of the most effective switching behaviors available in the market for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.

Product status link	
<a href="#">STB41N40DM6AG</a>	
Product summary	
Order code	STB41N40DM6AG
Marking	41N40DM6
Package	D <sup>2</sup> PAK
Packing	Tape and reel

## 1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	41	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	26	A
$I_{DM}^{(1)}$	Drain current (pulsed)	150	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	250	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	50	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	100	
$T_J$	Operating junction temperature range	-55 to 150	$^\circ\text{C}$
$T_{stg}$	Storage temperature range		

1. Pulse width limited by safe operating area
2.  $I_{SD} \leq 41 \text{ A}$ ,  $di/dt \leq 800 \text{ A}/\mu\text{s}$ ,  $V_{DS \text{ peak}} < V_{(BR)DSS}$ ,  $V_{DD} = 320 \text{ V}$
3.  $V_{DS} \leq 320 \text{ V}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.5	$^\circ\text{C/W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	30	

1. When mounted on an 1-inch<sup>2</sup> FR-4, 2 Oz copper board.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	6	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 100 \text{ V}$ )	760	mJ

## 2

## Electrical characteristics

$T_C = 25^\circ\text{C}$  unless otherwise specified

**Table 4. On-/off-states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	400			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, T_C = 125^\circ\text{C}^{(1)}$			100	$\mu\text{A}$
$I_{GSS}$	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 1$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 20.5 \text{ A}$		0.050	0.065	$\Omega$

1. Defined by design, not subject to production test.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	2310	-	pF
$C_{oss}$	Output capacitance		-	151	-	pF
$C_{rss}$	Reverse transfer capacitance		-	10	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 320 \text{ V}, V_{GS} = 0 \text{ V}$	-	450	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	1.3	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 320 \text{ V}, I_D = 41 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	53	-	nC
$Q_{gs}$	Gate-source charge		-	12	-	nC
$Q_{gd}$	Gate-drain charge		-	29	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 200 \text{ V}, I_D = 20.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	18	-	ns
$t_r$	Rise time	(see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	10.3	-	ns
$t_{d(off)}$	Turn-off delay time		-	46	-	ns
$t_f$	Fall time		-	9.4	-	ns

**Table 7. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		41	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		150	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 41 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 41 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}$	-	103		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	0.44		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	8.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 41 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$	-	180		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	1.5		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	17		A

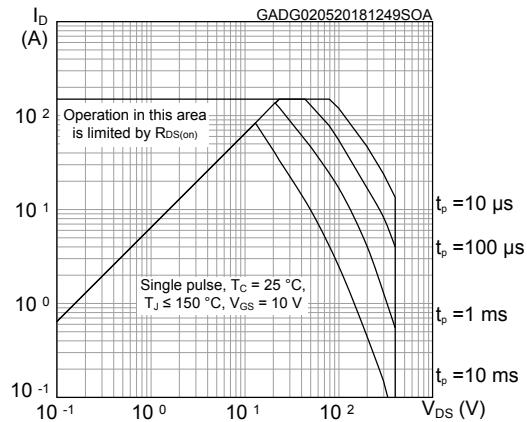
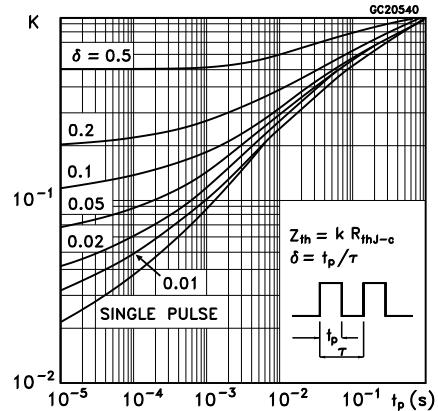
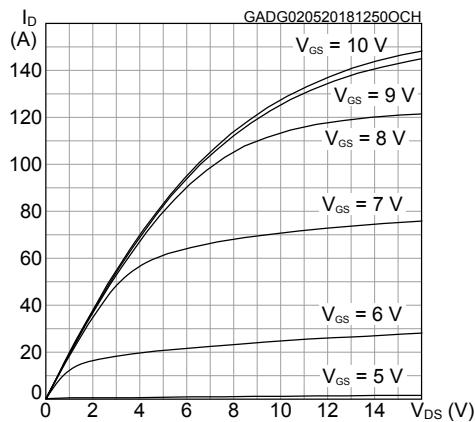
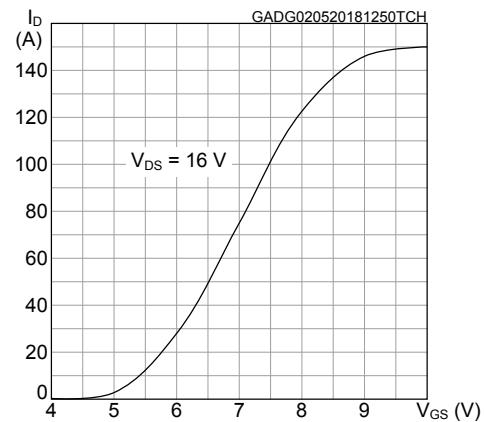
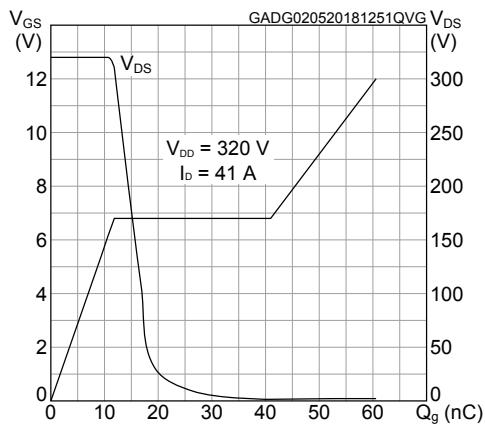
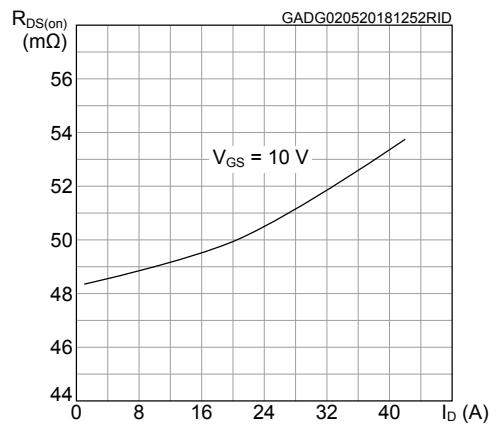
1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

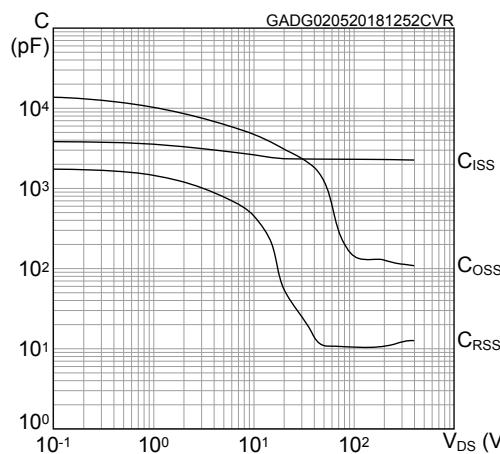
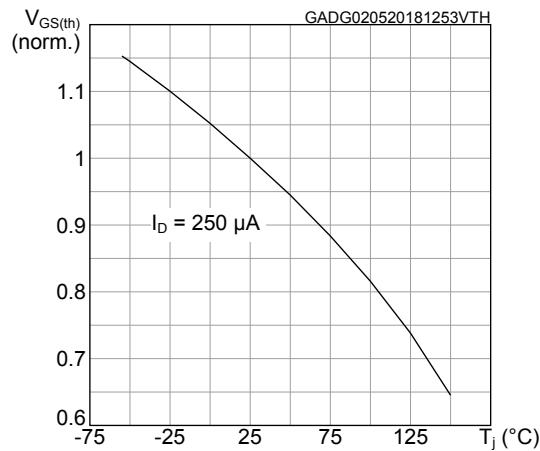
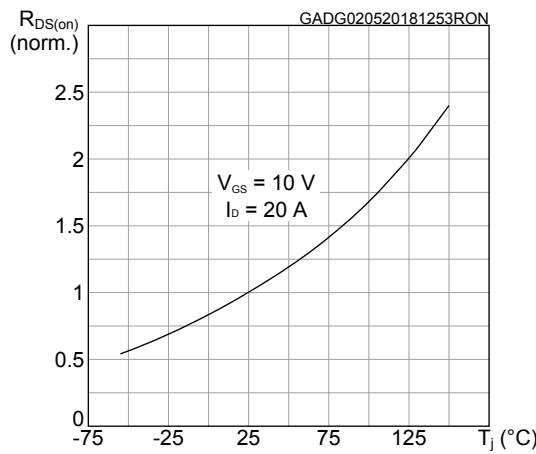
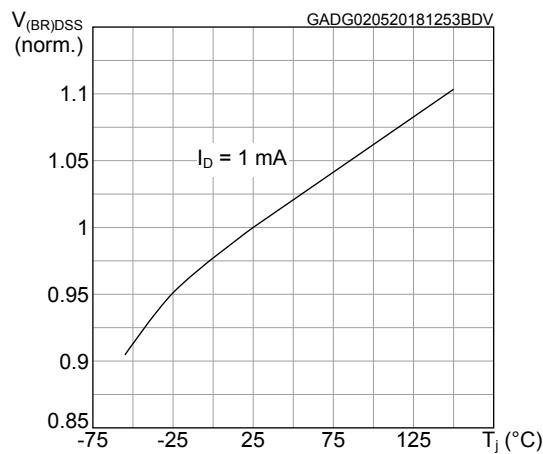
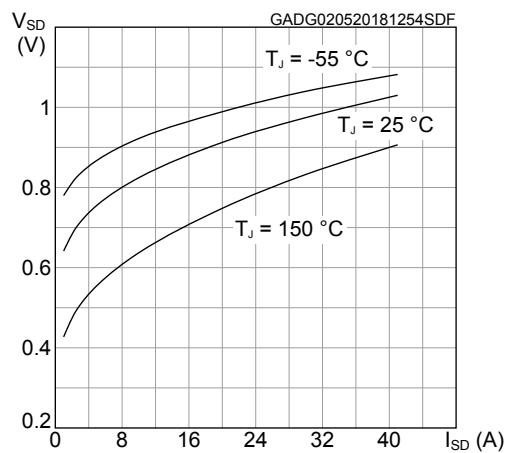
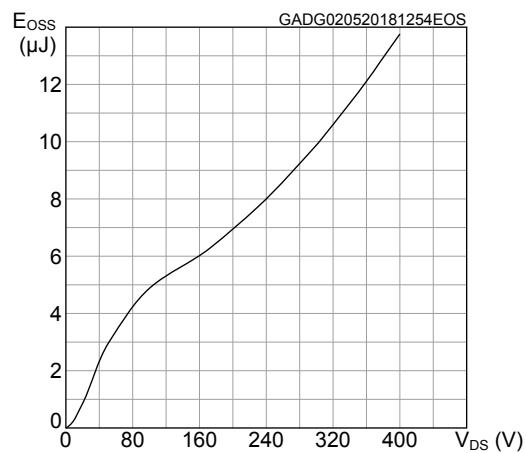
**Table 8. Gate-source Zener diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}, I_D = 0 \text{ A}$	$\pm 30$	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

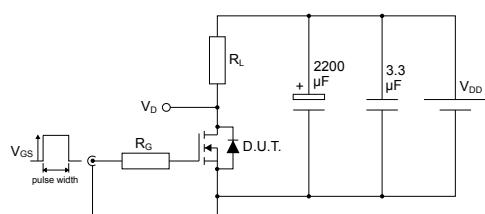
## 2.1 Electrical characteristics (curves)

**Figure 1. Safe operating area**

**Figure 2. Thermal impedance**

**Figure 3. Output characteristics**

**Figure 4. Transfer characteristics**

**Figure 5. Gate charge vs gate-source voltage**

**Figure 6. Static drain-source on-resistance**


**Figure 7. Capacitance variations**

**Figure 8. Normalized gate threshold voltage vs temperature**

**Figure 9. Normalized on-resistance vs temperature**

**Figure 10. Normalized V\_BR(DSS) vs temperature**

**Figure 11. Source-drain diode forward characteristics**

**Figure 12. Output capacitance stored energy**


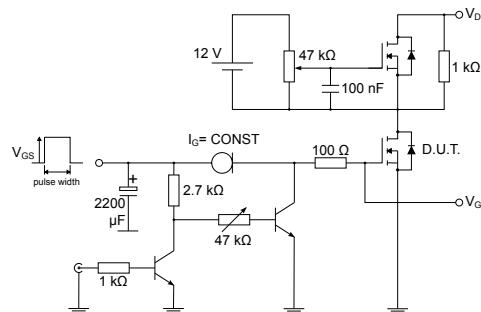
### 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**



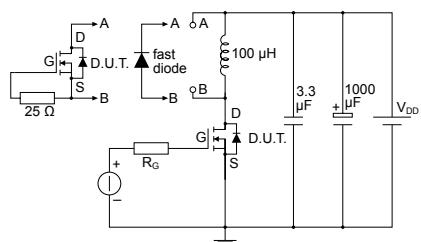
AM01468v1

**Figure 14. Test circuit for gate charge behavior**



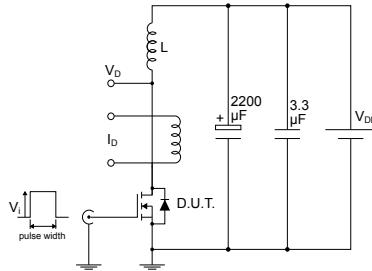
AM01469v1

**Figure 15. Test circuit for inductive load switching and diode recovery times**



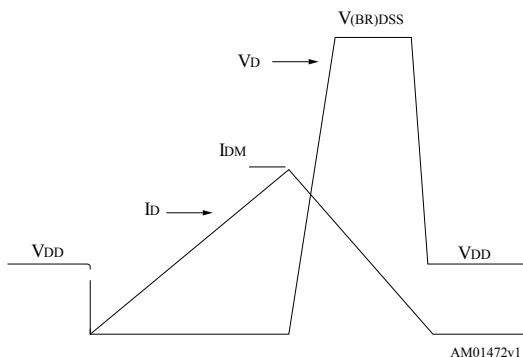
AM01470v1

**Figure 16. Unclamped inductive load test circuit**



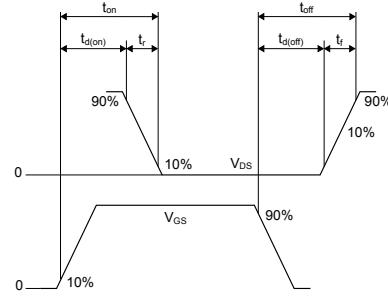
AM01471v1

**Figure 17. Unclamped inductive waveform**



AM01472v1

**Figure 18. Switching time waveform**



AM01473v1

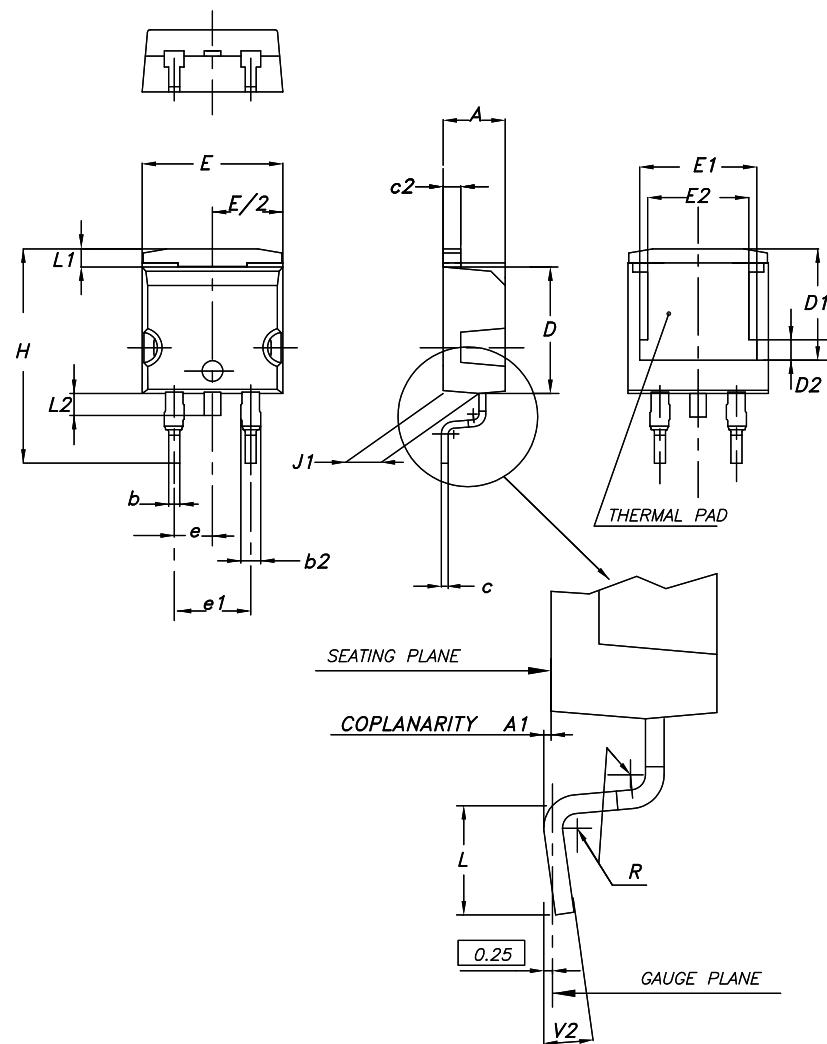
## 4

## Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

4.1 D<sup>2</sup>PAK (TO-263) type A2 package information

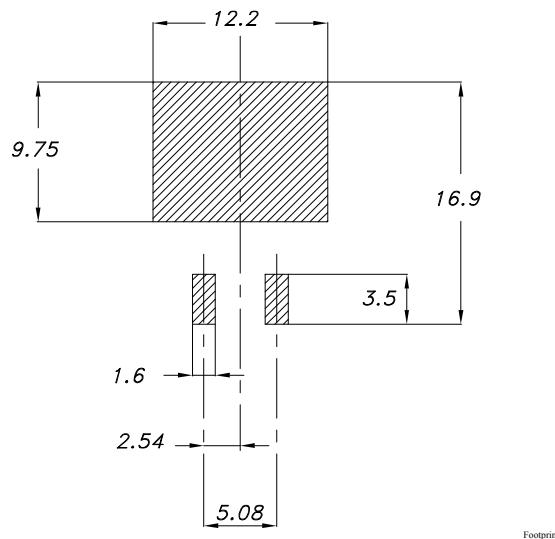
Figure 19. D<sup>2</sup>PAK (TO-263) type A2 package outline



0079457\_A2\_24

**Table 9.** D<sup>2</sup>PAK (TO-263) type A2 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10.00		10.40
E1	8.70	8.90	9.10
E2	7.30	7.50	7.70
e		2.54	
e1	4.88		5.28
H	15.00		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.40	
V2	0°		8°

**Figure 20.** D<sup>2</sup>PAK (TO-263) recommended footprint (dimensions are in mm)

## 4.2 D<sup>2</sup>PAK packing information

**Figure 21. D<sup>2</sup>PAK tape outline**

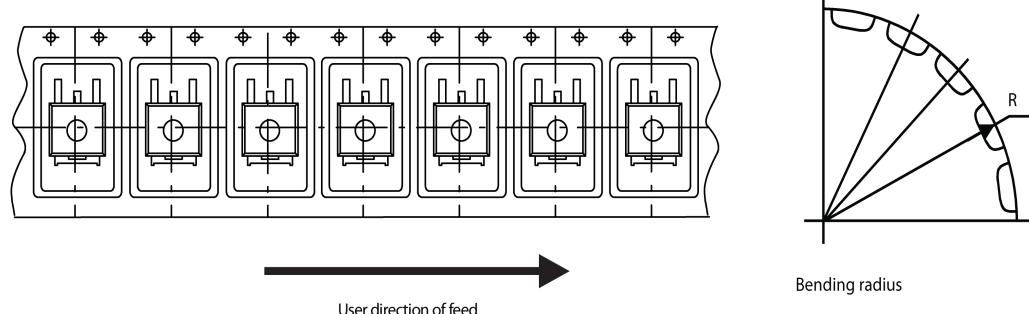
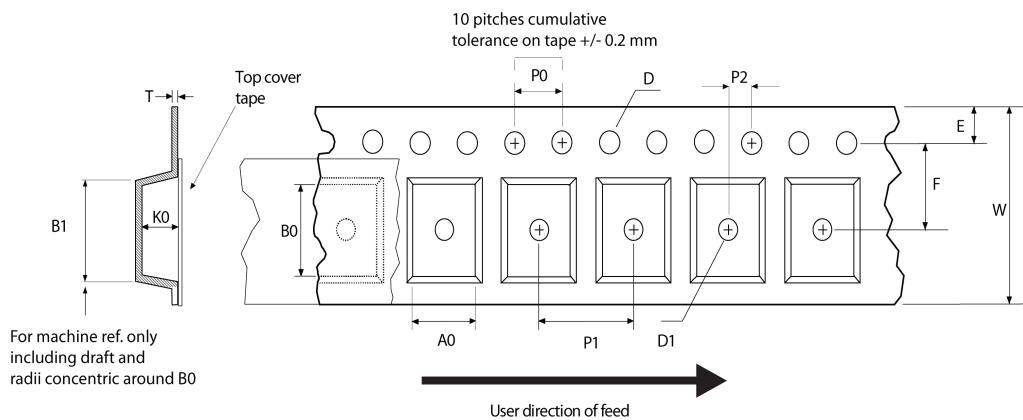
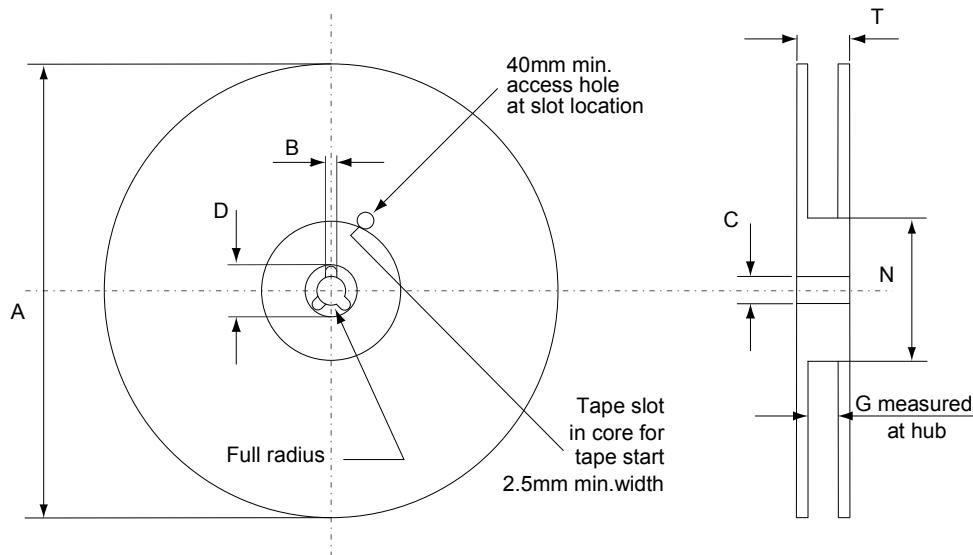


Figure 22. D<sup>2</sup>PAK reel outline

AM06038v1

Table 10. D<sup>2</sup>PAK tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1		Base quantity	1000
P2	1.9	2.1		Bulk quantity	1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

## Revision history

**Table 11. Document revision history**

Date	Version	Changes
17-May-2018	1	Initial release. The document status is production data.

## Contents

<b>1</b>	<b>Electrical ratings .....</b>	<b>2</b>
<b>2</b>	<b>Electrical characteristics.....</b>	<b>3</b>
<b>2.1</b>	Electrical characteristics (curves) .....	5
<b>3</b>	<b>Test circuits .....</b>	<b>7</b>
<b>4</b>	<b>Package information.....</b>	<b>8</b>
<b>4.1</b>	D <sup>2</sup> PAK (TO-263) type A2 package information .....	8
<b>4.2</b>	D <sup>2</sup> PAK packing information .....	9
	<b>Revision history .....</b>	<b>12</b>

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2018 STMicroelectronics – All rights reserved

# X-ON Electronics

Largest Supplier of Electrical and Electronic Components

***Click to view similar products for MOSFET category:***

***Click to view products by STMicroelectronics manufacturer:***

Other Similar products are found below :

[614233C](#) [648584F](#) [IRFD120](#) [JANTX2N5237](#) [FCA20N60\\_F109](#) [FDZ595PZ](#) [2SK2545\(Q,T\)](#) [405094E](#) [423220D](#) [TPCC8103,L1Q\(CM](#)  
[MIC4420CM-TR](#) [VN1206L](#) [SBVS138LT1G](#) [614234A](#) [715780A](#) [NTNS3166NZT5G](#) [SSM6J414TU,LF\(T](#) [751625C](#) [BUK954R8-60E](#)  
[NTE6400](#) [SQJ402EP-T1-GE3](#) [2SK2614\(TE16L1,Q\)](#) [2N7002KW-FAI](#) [DMN1017UCP3-7](#) [EFC2J004NUZTDG](#) [ECH8691-TL-W](#)  
[FCAB21350L1](#) [P85W28HP2F-7071](#) [DMN1053UCP4-7](#) [NTE221](#) [NTE2384](#) [NTE2903](#) [NTE2941](#) [NTE2945](#) [NTE2946](#) [NTE2960](#) [NTE2967](#)  
[NTE2969](#) [NTE2976](#) [NTE455](#) [NTE6400A](#) [NTE2910](#) [NTE2916](#) [NTE2956](#) [NTE2911](#) [DMN2080UCB4-7](#) [TK10A80W,S4X\(S](#)  
[SSM6P69NU,LF](#) [DMP22D4UFO-7B](#) [DMN1006UCA6-7](#)